



Dear MunEDA Friends & Users,

We are pleased to invite you to visit our MunEDA booth and workshops at 54th DAC Exhibition, Mon-Wed June 19-21 2017 Austin, TX (www.dac.com).

MunEDA booth # 1012 in main exhibition hall



Circuit Schematic Migration & IP Porting

[Learn more...](#)

Variation Analysis, PVT, Monte Carlo & High-Sigma

[Learn more...](#)

Circuit Sizing for Low Power, Yield & Reliability

[Learn more...](#)

54rd DAC Austin - Floorplan Schematic



WWW.DAC.COM

New: BTI-induced SRAM Bitcell Optimization

For arranging a meeting with MunEDA at DAC 2017 please contact us with:

info@muneda.com

New: Circuit Optimization for Radiation Hardening

MunEDA News at DAC 2017

- Advances in Custom Circuit Design Migration and IP Porting
- Low-Power Optimization of Custom IC Designs
- BTI Induced Dispersion: Challenges for SRAM Bit Cell Optimization
- Efficient and accurate high sigma analysis and optimization for
 - Memory I/O
 - Standard cells
 - SRAM bitcell, sensing, control including hierarchical large circuit analysis
- PCM targeting for debugging yield issues
- Full Custom Design for Reliability, Aging & Radiation Hardening

MunEDA DAC Special Topic: Low Power Circuit Sizing for IoT

- Why is multi-objective automated circuit sizing challenging for IoT designs.
- How can MunEDA automated sizing tools be leveraged to achieve high-performance and reliable to IoT designs.
- How are statistics incorporated into sizing to consider device mismatch and process centering.
- What is the technology behind the MunEDA automated sizing environment – with enough math/statistics to be interesting but not overwhelming.
- How can MunEDA sensitivity-based tools be useful to test and confirm and validate current intuition of my IoT designs

Ask for our special introduction Low Power Circuit Sizing for IoT, info@muneda.com

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See you all in Austin for 2017 MunEDA DAC Exhibition and Workshops – www.muneda.com